

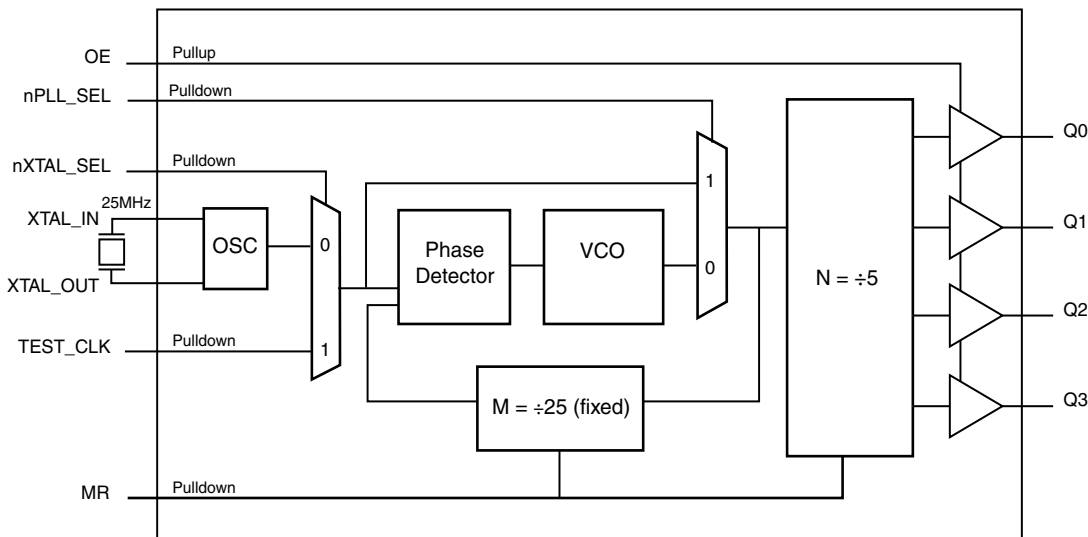
General Description

The 840024I is a four output LVCMOS/LVTTL Synthesizer optimized to generate Ethernet reference clock frequency. The 840024I uses IDT's 3RD generation low phase noise VCO technology and can achieve 1ps or lower typical random RMS phase jitter, easily meeting Ethernet jitter requirements. The 840024I is packaged in a small 20-pin TSSOP package.

Features

- Four LVCMOS / LVTTL outputs
- Selectable crystal oscillator interface or LVCMOS / LVTTL single-ended clock input
- Supports the following output frequency: 125MHz
- RMS phase jitter @125MHz (1.875MHz - 20MHz): 0.6ps (typical)
- Power supply modes:
Core/Output
3.3V/3.3V
3.3V/2.5V
2.5V/2.5V
- -40°C to 85°C ambient operating temperature
- Available in lead-free (RoHS 6) package

Block Diagram



Pin Assignment

| | | | |
|-----------|----|----|----------|
| nc | 1 | 20 | nc |
| nc | 2 | 19 | GND |
| nXTAL_SEL | 3 | 18 | Q0 |
| TEST_CLK | 4 | 17 | Q1 |
| OE | 5 | 16 | VDDO |
| MR | 6 | 15 | Q2 |
| nPLL_SEL | 7 | 14 | Q3 |
| VDDA | 8 | 13 | GND |
| nc | 9 | 12 | XTAL_IN |
| VDD | 10 | 11 | XTAL_OUT |

20-Lead TSSOP
6.5mm x 4.4mm x 0.925mm
package body
G Package
Top View

Table 1. Pin Descriptions

| Number | Name | Type | | Description |
|----------------|----------------------|--------|----------|--|
| 1, 2, 9, 20 | nc | Unused | | No connect pins. |
| 3 | nXTAL_SEL | Input | Pulldown | PLL reference select control input. See Table 3A. LVCMOS/LVTTL interface levels. |
| 4 | TEST_CLK | Input | Pulldown | Single-ended clock input. LVCMOS/LVTTL interface levels. |
| 5 | OE | Input | Pullup | Output enable control pin. See Table 3B. LVCMOS/LVTTL interface levels. |
| 6 | MR | Input | Pulldown | Master reset control pin. See Table 3C. LVCMOS/LVTTL interface levels. |
| 7 | nPLL_SEL | Input | Pulldown | PLL bypass control input. See Table 3D. LVCMOS/LVTTL interface levels. |
| 8 | V _{DDA} | Power | | Analog supply pin. |
| 10 | V _{DD} | Power | | Core supply pin. |
| 11, 12 | XTAL_OUT, XTAL_IN | Input | | Crystal oscillator interface. XTAL_IN is the input. XTAL_OUT is the output. |
| 13, 19 | GND | Power | | Power supply ground. |
| 14, 15, 17, 18 | Q3, Q2, Q1, Q0 | Output | | Single-ended clock outputs. 17Ω output impedance. LVCMOS/LVTTL interface levels. |
| 16 | V _{DDO} | Power | | Output supply pin. |

NOTE: *Pullup* and *Pulldown* refer to internal input resistors. See Table 2, *Pin Characteristics*, for typical values.

Table 2. Pin Characteristics

| Symbol | Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
|-----------------------|--|------------------------------|---------|---------|---------|-------|
| C _{IN} | Input Capacitance | | | 4 | | pF |
| C _{PD} | Power Dissipation Capacitance (per output) | | | 8 | | pF |
| R _{PULLUP} | Input Pullup Resistor | | | 51 | | kΩ |
| R _{PULLDOWN} | Input Pulldown Resistor | | | 51 | | kΩ |
| R _{OUT} | Output Impedance | V _{DDO} = 3.3V ± 5% | | 17 | | Ω |
| | | V _{DDO} = 2.5V ± 5% | | 21 | | Ω |

Function Tables

Table 3A. nXTAL_SEL PLL Reference Select Function Table

| nXTAL_SEL | PLL Reference Input |
|-------------|---------------------|
| 0 (default) | XTAL Interface |
| 1 | TEST_CLK |

Table 3B. Output Enable Function Table

| OE | Output Operation |
|-------------|--|
| 0 | Q[0:3] are disabled in high-impedance state. |
| 1 (default) | Q[0:3] are enabled. |

Table 3C. Master Reset Function Table

| MR | Reset Operation |
|-------------|--|
| 0 (default) | Normal operation, internal dividers are enabled. |
| 1 | Internal dividers are reset, Q[0:3] are disabled in logic low state. |

Table 3D. PLL Bypass Function Table

| nPLL_SEL | PLL Operation |
|-------------|--|
| 0 (default) | PLL is enabled |
| 1 | PLL is bypassed. The output frequency is equal to the selected reference frequency divided by the output divider of 5. |

Absolute Maximum Ratings

NOTE: Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics* or *AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

| Item | Rating |
|--|--|
| Supply Voltage, V_{DD} | 4.6V |
| Inputs, V_I XTAL_IN Other Inputs | 0V to V_{DD} -0.5V to $V_{DD} + 0.5V$ |
| Outputs, V_O | -0.5V to $V_{DDO} + 0.5V$ |
| Package Thermal Impedance, θ_{JA} | 86.7°C/W (0 mps) |
| Storage Temperature, T_{STG} | -65°C to 150°C |

DC Electrical Characteristics

Table 4A. Power Supply DC Characteristics, $V_{DD} = V_{DDO} = 3.3V \pm 5\%$, $T_A = -40^\circ\text{C}$ to 85°C

| Symbol | Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
|-----------|-----------------------|-----------------|-----------------|---------|----------|-------|
| V_{DD} | Core Supply Voltage | | 3.135 | 3.3 | 3.465 | V |
| V_{DDA} | Analog Supply Voltage | | $V_{DD} - 0.14$ | 3.3 | V_{DD} | V |
| V_{DDO} | Output Supply Voltage | | 3.135 | 3.3 | 3.465 | V |
| I_{DD} | Core Supply Current | | | | 90 | mA |
| I_{DDA} | Analog Supply Current | | | | 14 | mA |
| I_{DDO} | Output Supply Current | No Load | | | 8 | mA |

Table 4B. Power Supply DC Characteristics, $V_{DD} = 3.3V \pm 5\%$, $V_{DDO} = 2.5V \pm 5\%$, $T_A = -40^\circ\text{C}$ to 85°C

| Symbol | Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
|-----------|-----------------------|-----------------|-----------------|---------|----------|-------|
| V_{DD} | Core Supply Voltage | | 3.135 | 3.3 | 3.465 | V |
| V_{DDA} | Analog Supply Voltage | | $V_{DD} - 0.14$ | 3.3 | V_{DD} | V |
| V_{DDO} | Output Supply Voltage | | 2.375 | 2.5 | 2.625 | V |
| I_{DD} | Core Supply Current | | | | 90 | mA |
| I_{DDA} | Analog Supply Current | | | | 14 | mA |
| I_{DDO} | Output Supply Current | No Load | | | 8 | mA |

Table 4C. Power Supply DC Characteristics, $V_{DD} = V_{DDO} = 2.5V \pm 5\%$, $T_A = -40^\circ\text{C}$ to 85°C

| Symbol | Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
|-----------|-----------------------|-----------------|-----------------|---------|----------|-------|
| V_{DD} | Core Supply Voltage | | 2.375 | 2.5 | 2.625 | V |
| V_{DDA} | Analog Supply Voltage | | $V_{DD} - 0.14$ | 2.5 | V_{DD} | V |
| V_{DDO} | Output Supply Voltage | | 2.375 | 2.5 | 2.625 | V |
| I_{DD} | Core Supply Current | | | | 90 | mA |
| I_{DDA} | Analog Supply Current | | | | 14 | mA |
| I_{DDO} | Output Supply Current | No Load | | | 8 | mA |

Table 4D. LVCMOS/LVTTL DC Characteristics, $T_A = -40^{\circ}\text{C}$ to 85°C

| Symbol | Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
|----------|---------------------|--|---------|---------|----------------|---------------|
| V_{IH} | Input High Voltage | $V_{DD} = 3.465\text{V}$ | 2 | | $V_{DD} + 0.3$ | V |
| | | $V_{DD} = 2.625\text{V}$ | 1.7 | | $V_{DD} + 0.3$ | V |
| V_{IL} | Input Low Voltage | $V_{DD} = 3.465\text{V}$ | -0.3 | | 0.8 | V |
| | | $V_{DD} = 2.625\text{V}$ | -0.3 | | 0.7 | V |
| I_{IH} | Input High Current | OE $V_{DD} = V_{IN} = 3.465\text{V}$ or 2.625V | | | 5 | μA |
| | | TEST_CLK, MR, nXTAL_SEL, nPLL_SEL $V_{DD} = V_{IN} = 3.465\text{V}$ or 2.625V | | | 150 | μA |
| I_{IL} | Input Low Current | OE $V_{DD} = 3.465\text{V}$ or 2.625V , $V_{IN} = 0\text{V}$ | -150 | | | μA |
| | | TEST_CLK, MR, nXTAL_SEL, nPLL_SEL $V_{DD} = 3.465\text{V}$ or 2.625V , $V_{IN} = 0\text{V}$ | -5 | | | μA |
| V_{OH} | Output High Voltage | $V_{DDO} = 3.3\text{V} \pm 5\%$; $I_{OH} = -12\text{mA}$ | 2.6 | | | V |
| | | $V_{DDO} = 2.5\text{V} \pm 5\%$; $I_{OH} = -12\text{mA}$ | 1.8 | | | V |
| V_{OL} | Output Low Voltage | $V_{DDO} = 3.3\text{V} \pm 5\%$ or $2.5\text{V} \pm 5\%$; $I_{OL} = 12\text{mA}$ | | | 0.5 | V |

Table 5. Crystal Characteristics

| Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
|------------------------------------|-----------------|-------------|---------|---------|----------|
| Mode of Oscillation | | Fundamental | | | |
| Frequency | | | 25 | | MHz |
| Equivalent Series Resistance (ESR) | | | | 50 | Ω |
| Shunt Capacitance | | | | 7 | pF |

NOTE: Characterized using an 18pF parallel resonant crystal.

AC Electrical Characteristics

Table 6A. AC Characteristics, $V_{DD} = V_{DDO} = 3.3V \pm 5\%$, $T_A = -40^\circ\text{C}$ to 85°C

| Symbol | Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
|----------------------|-----------------------------------|--|---------|---------|---------|-------|
| f_{OUT} | Output Frequency | | | 125 | | MHz |
| $t_{sk(o)}$ | Output Skew; NOTE 1, 2 | | | 20 | 60 | ps |
| $t_{jit}(\emptyset)$ | RMS Phase Jitter (Random); NOTE 3 | 125MHz, Integration Range: 1.875MHz – 20MHz | | 0.604 | | ps |
| t_{LOCK} | PLL Lock Time | | | 50 | 100 | ms |
| t_R / t_F | Output Rise/Fall Time | 20% to 80% | 250 | 400 | 750 | ps |
| odc | Output Duty Cycle | | 42 | 50 | 58 | % |

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfm. The device will meet specifications after thermal equilibrium has been reached under these conditions.

NOTE: Characterized with crystal input.

NOTE 1: Defined as skew between outputs at the same supply voltage and with equal load conditions. Measured at $V_{DDO}/2$.

NOTE 2: This parameter is defined in accordance with JEDEC Standard 65.

NOTE 3: Refer to phase noise plots.

Table 6B. AC Characteristics, $V_{DD} = 3.3V \pm 5\%$, $V_{DDO} = 2.5V \pm 5\%$, $T_A = -40^\circ\text{C}$ to 85°C

| Symbol | Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
|----------------------|-----------------------------------|--|---------|---------|---------|-------|
| f_{OUT} | Output Frequency | | | 125 | | MHz |
| $t_{sk(o)}$ | Output Skew; NOTE 1, 2 | | | 20 | 60 | ps |
| $t_{jit}(\emptyset)$ | RMS Phase Jitter (Random); NOTE 3 | 125MHz, Integration Range: 1.875MHz – 20MHz | | 0.546 | | ps |
| t_{LOCK} | PLL Lock Time | | | 50 | 100 | ms |
| t_R / t_F | Output Rise/Fall Time | 20% to 80% | 250 | 400 | 750 | ps |
| odc | Output Duty Cycle | | 46 | 50 | 54 | % |

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfm. The device will meet specifications after thermal equilibrium has been reached under these conditions.

NOTE: Characterized with crystal input.

NOTE 1: Defined as skew between outputs at the same supply voltage and with equal load conditions. Measured at $V_{DDO}/2$.

NOTE 2: This parameter is defined in accordance with JEDEC Standard 65.

NOTE 3: Refer to phase noise plots.

Table 6C. AC Characteristics, $V_{DD} = V_{DDO} = 2.5V \pm 5\%$, $T_A = -40^\circ\text{C}$ to 85°C

| Symbol | Parameter | Test Conditions | Minimum | Typical | Maximum | Units |
|----------------------|-----------------------------------|--|---------|---------|---------|-------|
| f_{OUT} | Output Frequency | | | 125 | | MHz |
| $t_{sk(o)}$ | Output Skew; NOTE 1, 2 | | | 20 | 60 | ps |
| $t_{jit}(\emptyset)$ | RMS Phase Jitter (Random); NOTE 3 | 125MHz, Integration Range: 1.875MHz – 20MHz | | 0.544 | | ps |
| t_{LOCK} | PLL Lock Time | | | 50 | 100 | ms |
| t_R / t_F | Output Rise/Fall Time | 20% to 80% | 250 | 400 | 750 | ps |
| odc | Output Duty Cycle | | 42 | 50 | 58 | % |

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfm. The device will meet specifications after thermal equilibrium has been reached under these conditions.

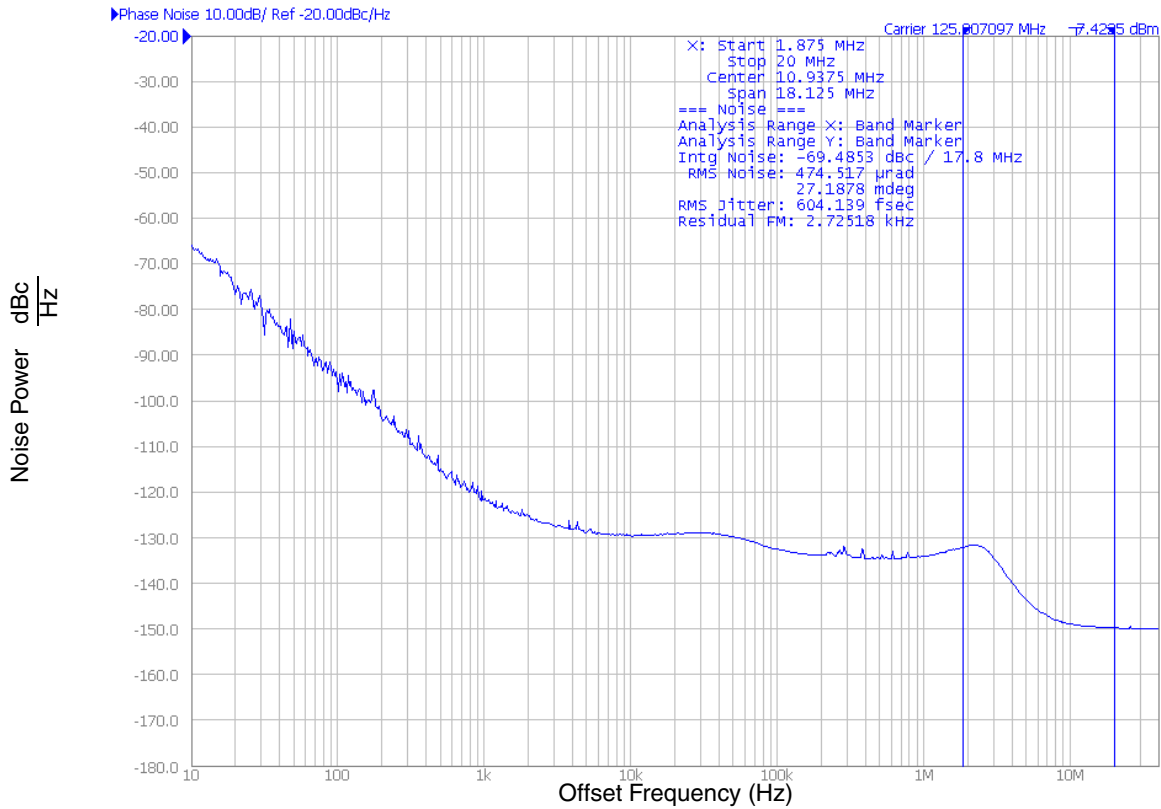
NOTE: Characterized with crystal input.

NOTE 1: Defined as skew between outputs at the same supply voltage and with equal load conditions. Measured at $V_{DDO}/2$.

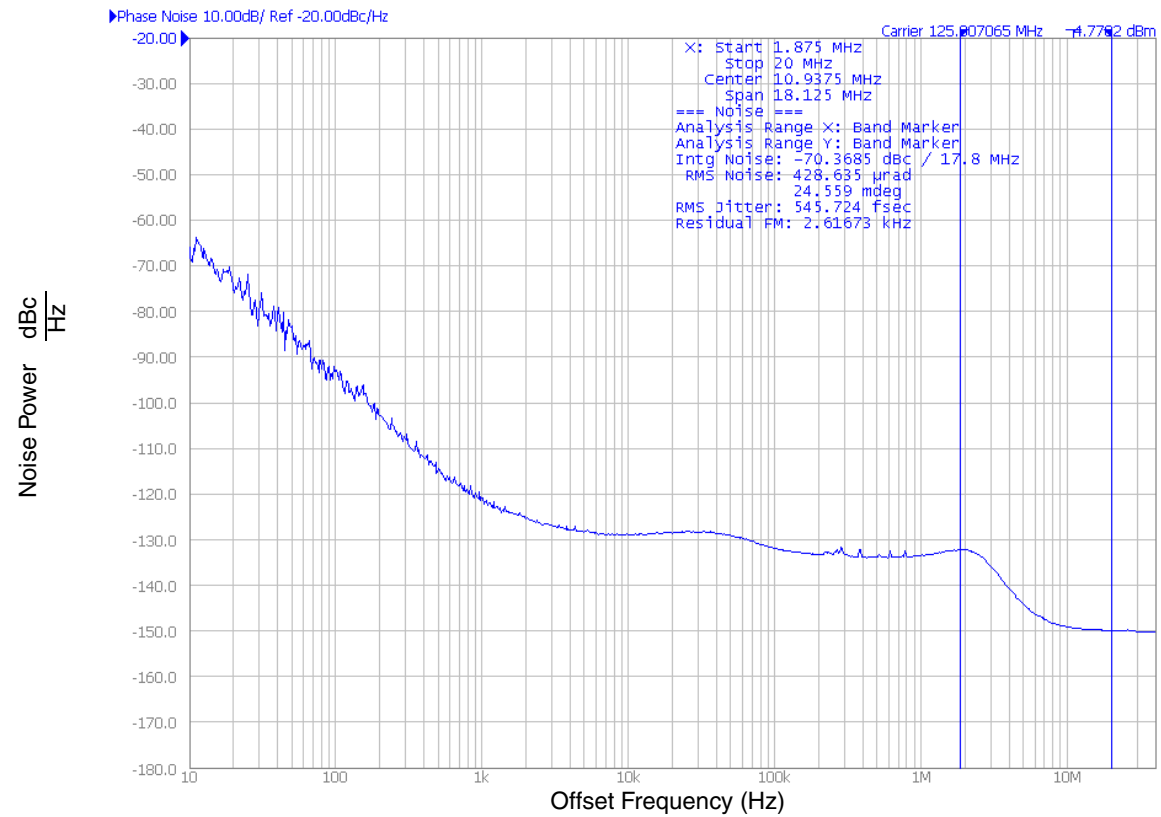
NOTE 2: This parameter is defined in accordance with JEDEC Standard 65.

NOTE 3: Refer to phase noise plots.

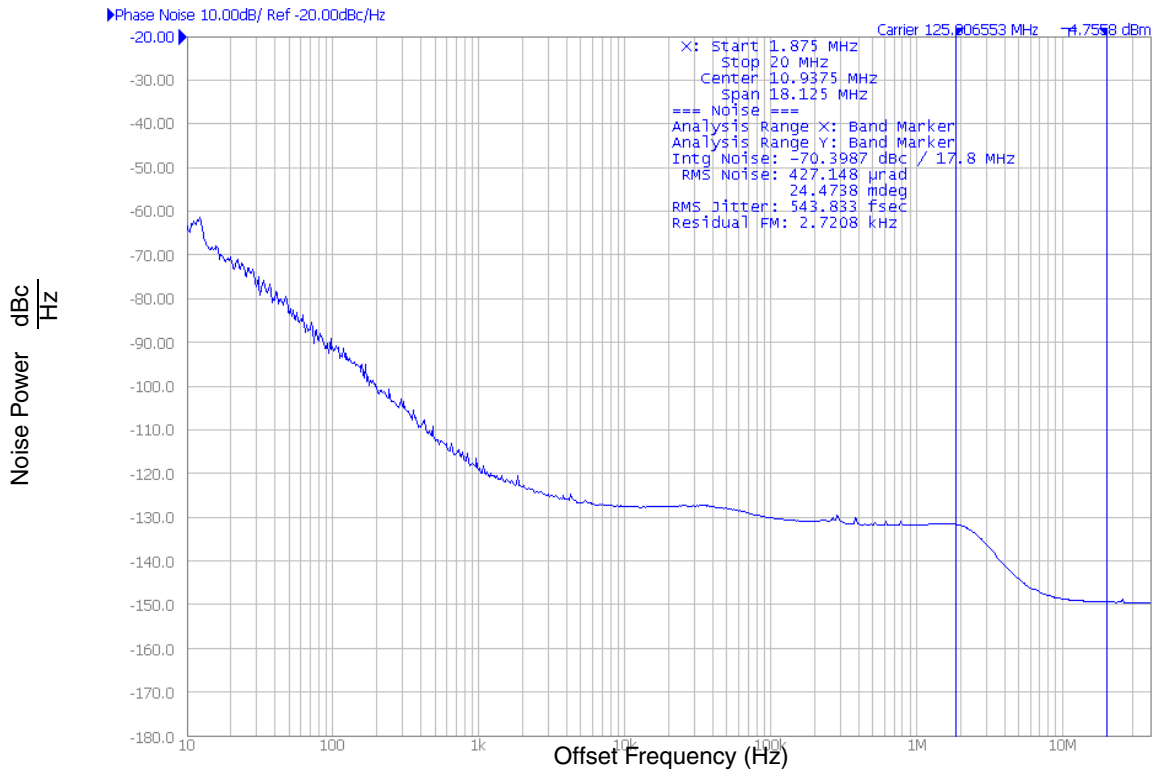
Typical Phase Noise at 125MHz (3.3V/3.3V)



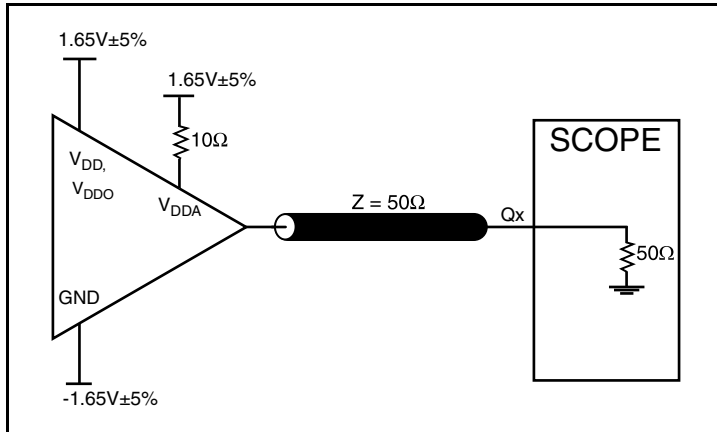
Typical Phase Noise at 125MHz (3.3V/2.5V)



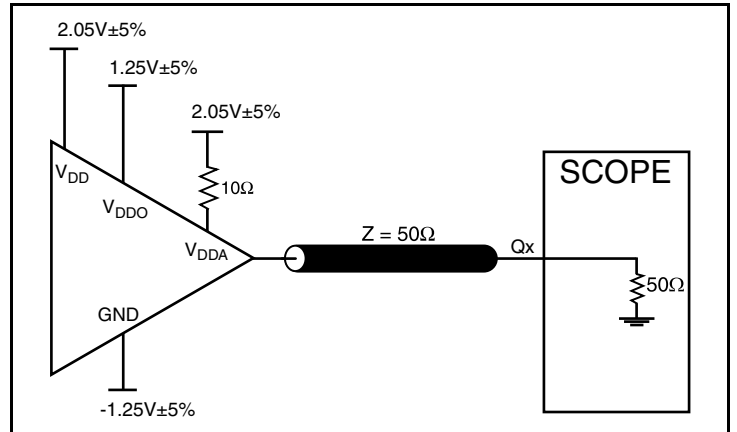
Typical Phase Noise at 125MHz (2.5V/2.5V)



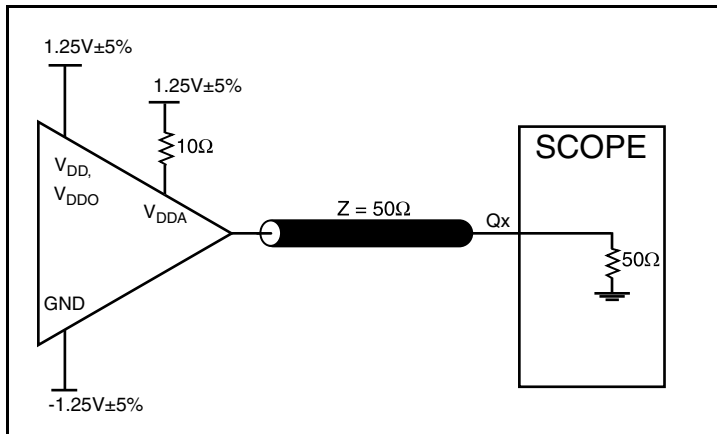
Parameter Measurement Information



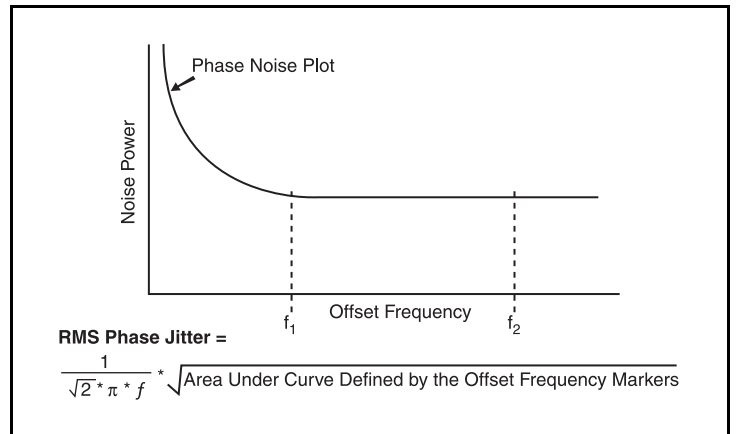
3.3V Core/3.3V LVCMOS Output Load AC Test Circuit



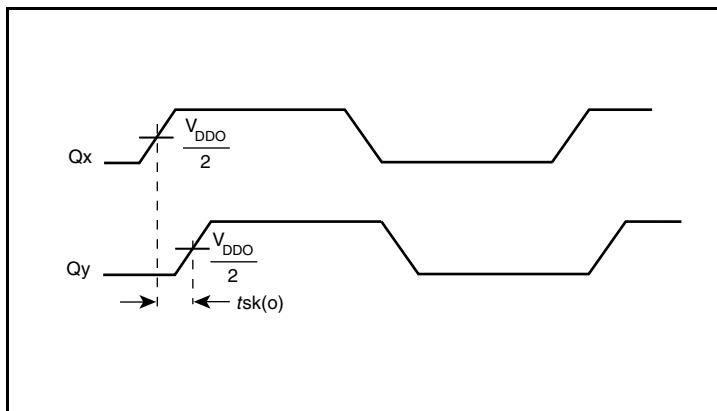
3.3V Core/2.5V LVCMOS Output Load AC Test Circuit



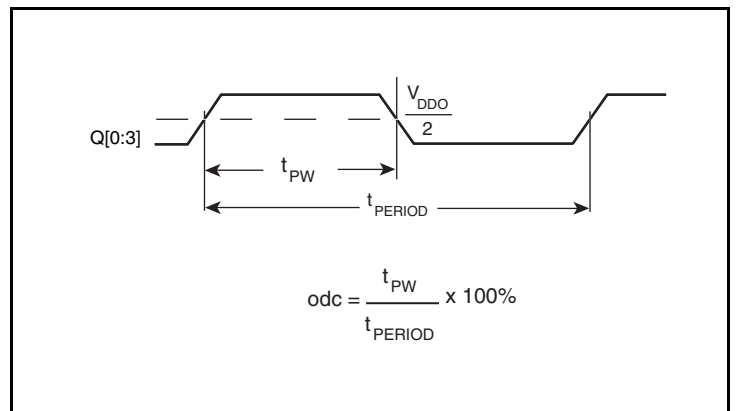
2.5V Core/2.5V LVCMOS Output Load AC Test Circuit



RMS Phase Jitter

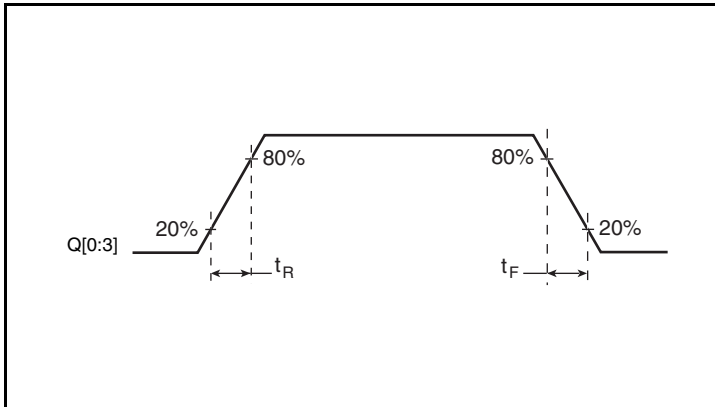


Output Skew



Output Duty Cycle/Pulse Width/Period

Parameter Measurement Information, continued



Output Rise/Fall Time

Applications Information

Recommendations for Unused Input and Output Pins

Inputs:

TEST_CLK Input

For applications not requiring the use of the test clock, it can be left floating. Though not required, but for additional protection, a $1\text{k}\Omega$ resistor can be tied from the TEST_CLK to ground.

LVCMOS Control Pins

All control pins have internal pullups or pulldowns; additional resistance is not required but can be added for additional protection. A $1\text{k}\Omega$ resistor can be used.

Outputs:

LVCMOS Outputs

All unused LVCMOS outputs can be left floating. There should be no trace attached.

Overdriving the XTAL Interface

The XTAL_IN input can be overdriven by an LVCMOS driver or by one side of a differential driver through an AC coupling capacitor. The XTAL_OUT pin can be left floating. The amplitude of the input signal should be between 500mV and 1.8V and the slew rate should not be less than 0.2V/nS. For 3.3V LVCMOS inputs, the amplitude must be reduced from full swing to at least half the swing in order to prevent signal interference with the power rail and to reduce internal noise. *Figure 1A* shows an example of the interface diagram for a high speed 3.3V LVCMOS driver. This configuration requires that the sum of the output impedance of the driver (R_o) and the series resistance (R_s) equals the transmission line impedance. In addition, matched termination at the crystal input will attenuate the signal in half. This

can be done in one of two ways. First, R_1 and R_2 in parallel should equal the transmission line impedance. For most 50Ω applications, R_1 and R_2 can be 100Ω. This can also be accomplished by removing R_1 and changing R_2 to 50Ω. The values of the resistors can be increased to reduce the loading for a slower and weaker LVCMOS driver. *Figure 1B* shows an example of the interface diagram for an LVPECL driver. This is a standard LVPECL termination with one side of the driver feeding the XTAL_IN input. It is recommended that all components in the schematics be placed in the layout. Though some components might not be used, they can be utilized for debugging purposes. The datasheet specifications are characterized and guaranteed by using a quartz crystal as the input.

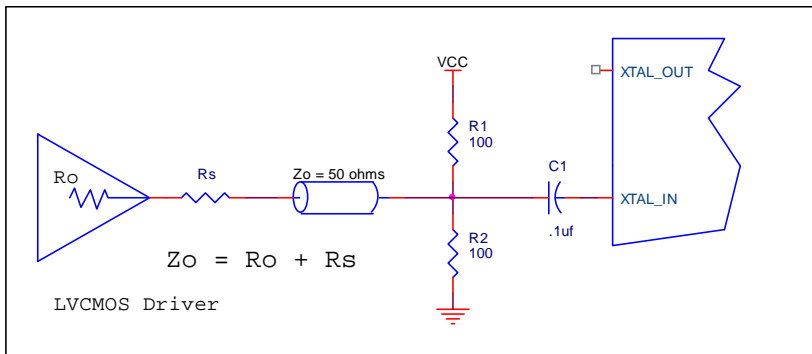


Figure 1A. General Diagram for LVCMOS Driver to XTAL Input Interface

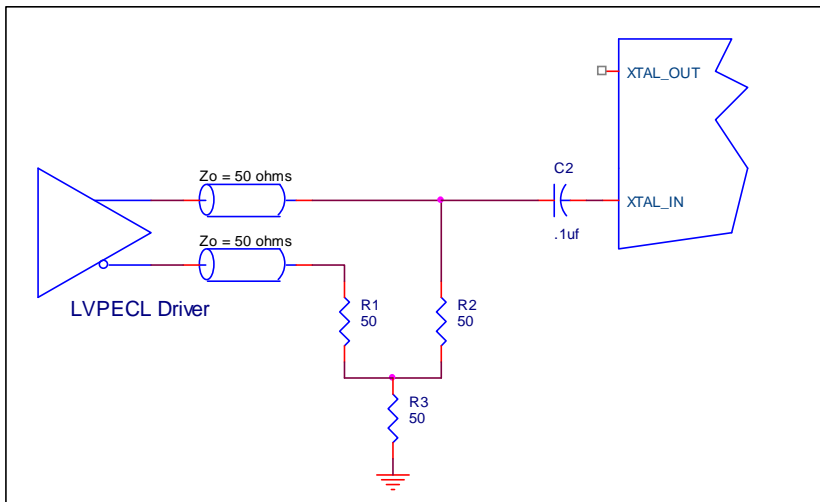


Figure 1B. General Diagram for LVPECL Driver to XTAL Input Interface

Schematic Layout

Figure 2 shows an example of 840024I application schematic. In this example, the device is operated at $V_{DD} = V_{DDO} = 3.3V$. An 18pF parallel resonant 25MHz crystal is used. The load capacitance $C1 = 22pF$ and $C2 = 22pF$ are recommended for frequency accuracy. Depending on the parasitics of the printed circuit board layout, these values might require a slight adjustment to optimize the frequency accuracy. Crystals with other load capacitance specifications can be used. This will required adjusting $C1$ and $C2$.

As with any high speed analog circuitry, the power supply pins are vulnerable to noise. To achieve optimum jitter performance, power

supply isolation is required. The 840024I provides separate power supplies to isolate from coupling into the internal PLL.

In order to achieve the best possible filtering, it is recommended that the placement of the filter components be on the device side of the PCB as close to the power pins as possible. If space is limited, the 0.1uF capacitor in each power pin filter should be placed on the device side of the PCB and the other components can be placed on the opposite side.

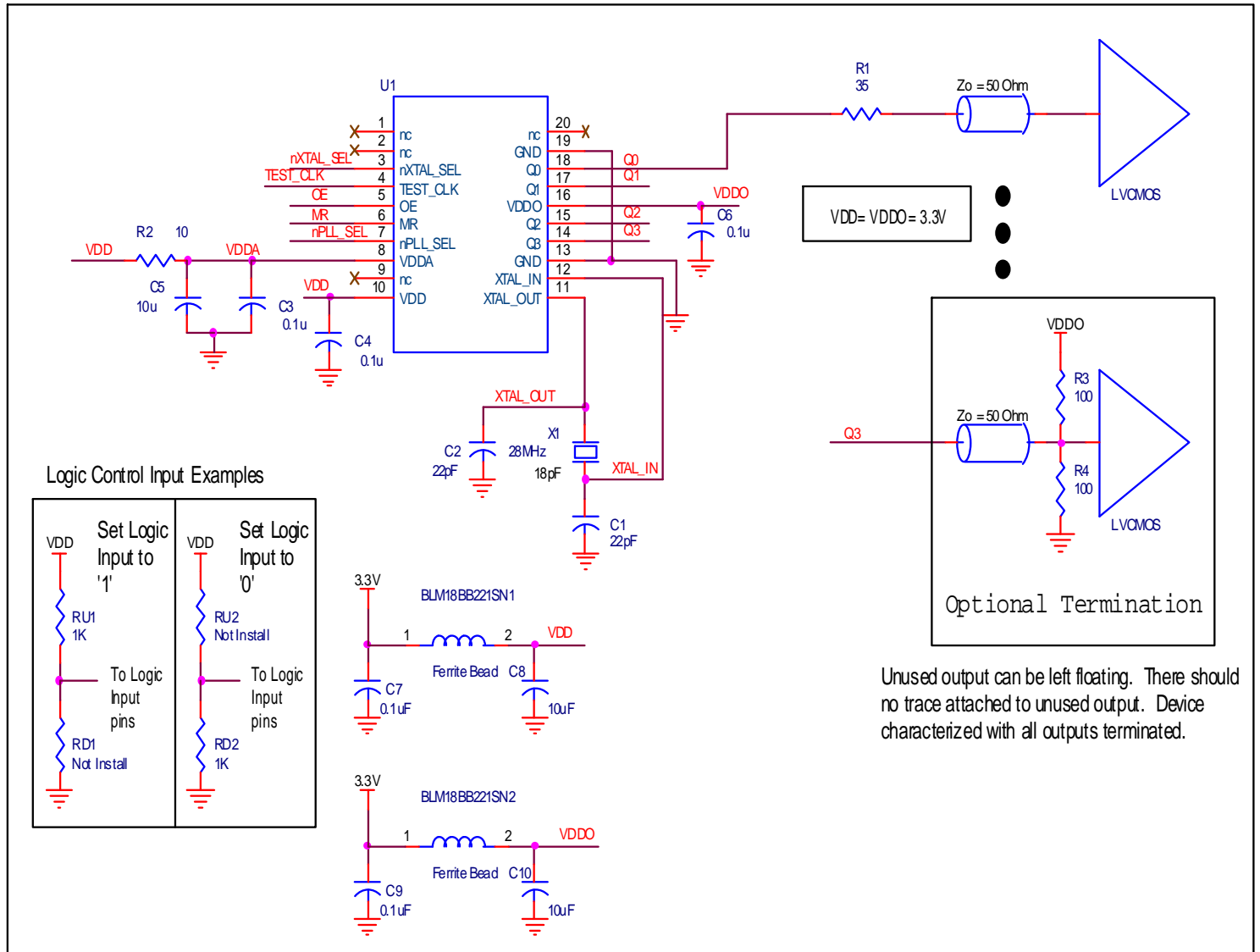


Figure 2. 840024I Application Schematic

Power supply filter recommendations are a general guideline to be used for reducing external noise from coupling into the devices. The filter performance is designed for wide range of noise frequencies. This low-pass filter starts to attenuate noise at approximately 10kHz. If a specific frequency noise component is known, such as switching power supply frequencies, it is recommended that component values be adjusted and if required, additional filtering be added. Additionally,

good general design practices for power plane voltage stability suggests adding bulk capacitances in the local area of all devices.

The schematic example focuses on functional connections and is not configuration specific. Refer to the pin description and functional tables in the datasheet to ensure the logic control inputs are properly set.

Power Considerations

This section provides information on power dissipation and junction temperature for the 840024I. Equations and example calculations are also provided.

1. Power Dissipation.

The total power dissipation for the 840024I is the sum of the core power plus the analog power plus the output power dissipated into the load. The following is the power dissipation for $V_{DD} = 3.3V + 5\% = 3.465V$, which gives worst case results.

- Power (core)_{MAX} = $V_{DD_MAX} * (I_{DD} + I_{DDA} + I_{DDO}) = 3.465V * (90mA + 14mA + 8mA) = \mathbf{388.1mW}$

Dynamic Power Dissipation at 125MHz

$$\text{Power (125MHz)} = C_{PD} * \text{Frequency} * (V_{DD})^2 = 8pF * 125MHz * (3.465V)^2 = \mathbf{12mW \text{ per output}}$$

$$\text{Total Power (125MHz)} = 12mW * 4 = \mathbf{48mW}$$

Total Power Dissipation

- Total Power**
= Power (core)_{MAX} + Power (125MHz)
= 388.1mW + 48mW
= **436.1mW**

2. Junction Temperature.

Junction temperature, T_j , is the temperature at the junction of the bond wire and bond pad directly affects the reliability of the device. The maximum recommended junction temperature is 125°C. Limiting the internal transistor junction temperature, T_j , to 125°C ensures that the bond wire and bond pad temperature remains below 125°C.

The equation for T_j is as follows: $T_j = \theta_{JA} * Pd_total + T_A$

T_j = Junction Temperature

θ_{JA} = Junction-to-Ambient Thermal Resistance

Pd_total = Total Device Power Dissipation (example calculation is in section 1 above)

T_A = Ambient Temperature

In order to calculate junction temperature, the appropriate junction-to-ambient thermal resistance θ_{JA} must be used. Assuming no air flow and a multi-layer board, the appropriate value is 86.7°C/W per Table 7 below.

Therefore, T_j for an ambient temperature of 85°C with all outputs switching is:

$$85^\circ\text{C} + 0.436\text{W} * 86.7^\circ\text{C/W} = 122.8^\circ\text{C}. \text{ This is below the limit of } 125^\circ\text{C}.$$

This calculation is only an example. T_j will obviously vary depending on the number of loaded outputs, supply voltage, air flow and the type of board (multi-layer).

Table 7. Thermal Resistance θ_{JA} for 20 Lead TSSOP, Forced Convection

| θ_{JA} vs. Air Flow | | | |
|---|----------|----------|----------|
| Meters per Second | 0 | 1 | 2.5 |
| Multi-Layer PCB, JEDEC Standard Test Boards | 86.7°C/W | 82.4°C/W | 80.2°C/W |

Reliability Information

Table 8. θ_{JA} vs. Air Flow Table for a 20 Lead TSSOP

| θ_{JA} vs. Air Flow | | | |
|---|----------|----------|----------|
| Meters per Second | 0 | 1 | 2.5 |
| Multi-Layer PCB, JEDEC Standard Test Boards | 86.7°C/W | 82.4°C/W | 80.2°C/W |

Transistor Count

The transistor count for ICS40024I is: 3093

Package Outline and Package Dimensions

Package Outline - G Suffix for 20 Lead TSSOP

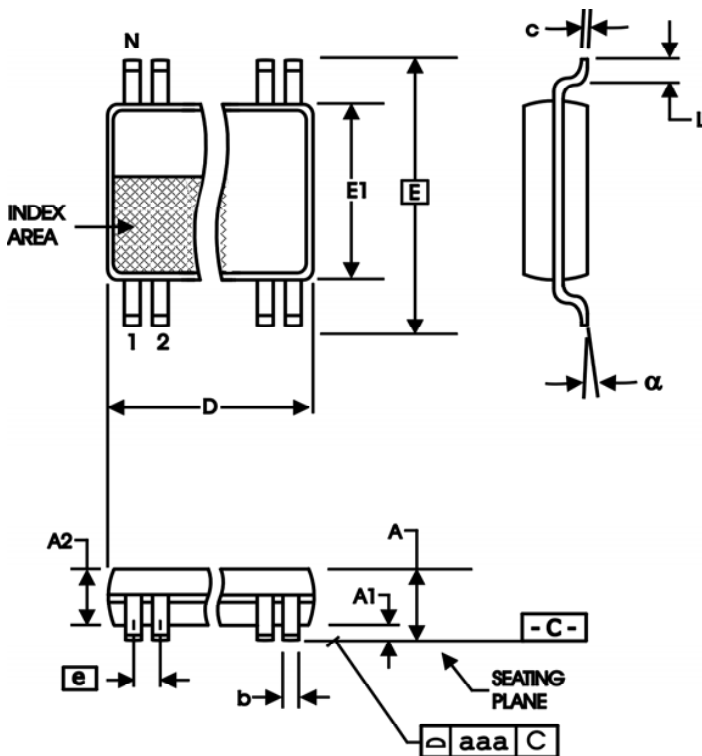


Table 9. Package Dimensions

| All Dimensions in Millimeters | | |
|-------------------------------|------------|---------|
| Symbol | Minimum | Maximum |
| N | 20 | |
| A | | 1.20 |
| A1 | 0.05 | 0.15 |
| A2 | 0.80 | 1.05 |
| b | 0.19 | 0.30 |
| c | 0.09 | 0.20 |
| D | 6.40 | 6.60 |
| E | 6.40 Basic | |
| E1 | 4.30 | 4.50 |
| e | 0.65 Basic | |
| L | 0.45 | 0.75 |
| α | 0° | 8° |
| aaa | | 0.10 |

Reference Document: JEDEC Publication 95, MO-153

Ordering Information

Table 10. Ordering Information

| Part/Order Number | Marking | Package | Shipping Packaging | Temperature |
|-------------------|--------------|---------------------------|--------------------|---------------|
| 840024BGILF | ICS840024BIL | "Lead-Free" 20 Lead TSSOP | Tube | -40°C to 85°C |
| 840024BGILFT | ICS840024BIL | "Lead-Free" 20 Lead TSSOP | Tape & Reel | -40°C to 85°C |

Revision History Sheet

| Rev | Table | Page | Description of Change | Date |
|-----|--------------------------------|-------------------|---|-----------|
| B | | 1 | Block Diagram - corrected nXTAL_SEL to select XTAL when LOW (0) and select TEST_CLK when HIGH (1). | 8/30/2012 |
| C | 4A - 4C 6A - 6C | 4 6 | Output Supply Current, Test Conditions: Added 'No Load'. Added NOTE: Use XTAL input. | 12/6/12 |
| C | Features 4A - 4C 6A - 6C | 1 4 6 13 | Deleted 17Ω Output Impedance. RMS Phase Jitter from 0.604ps to 0.6ps I _{DDA} from 12mA to 14mA Deleted NOTE: Use XTAL input. Added NOTE: Characterized with crystal input. Updated Power Considerations for 14mA | 1/11/13 |
| C | | | Updated data sheet format. | 4/3/15 |

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